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region with a second semiconductor material, wherein the first and second semiconductor materials are different semiconductor materials.

16. The method of claim 15, wherein the forming comprises:

providing at least one cavity in the substrate; and epitaxially growing the second semiconductor material from one or more surfaces of the at least one cavity to form the at least one region.

- 17. The method of claim 13, further comprising forming, 10 before the fabricating, multiple fins extending from the substrate, wherein the fabricating comprises fabricating at least one region of the first p-type region, first n-type region, second p-type region, or second n-type region to comprise one or more fins of the multiple fins of the substrate.
- 18. The structure of claim 1, wherein the first n-type region is disposed directly within the n-type well of the substrate, and wherein the second p-type region is disposed directly within the p-type well of the substrate.
- 19. The structure of claim 1, wherein the first p-type 20 region and the first n-type region are spaced from one another, and wherein the second p-type region and the second n-type region are spaced from one another.

\* \* \* \* \*